## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | WANG ET AL. | Examiner | Art Unit | Marcus Charles | 3682 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,271,967	12-1993	Kramer et al.	427/455
*	В	US-5,326,645	07-1994	Ashary et al.	428/552
*	С	US-5,622,753	04-1997	Shepley et al.	427/453
*	D	US-5,714,205	02-1998	Marantz et al.	427/449
*	Е	US-6,089,999	07-2000	Imaida et al.	474/18
*	F	US-6,258,416	07-2001	Seitz, Michael Walter	427/449
*	G	US-6,367,151	04-2002	Schlegel et al.	29/888.09
*	Н	US-6,435,830	08-2002	Allen et al.	416/193A
*	ı	US-2004/0248678	12-2004	Kapaan et al.	474/008
	J	US-			
	К	US-	<u> </u>		-
	L	US-			
	М	US-			······································

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP (2000-271729) A	10-2000	Japan		B21B 27/00
	0	JP (2003-254412) A	09-2003	Japan	Tanigawa et al.	F16H 57/02
	Р	EP (0637695) A1	02-1995	European	Van Brakel et al	384/463
	Q	EP (1281786) A1	02-2003	European	LeCoester	C23C 4/12
	R	EP (1209246) A1	05-2002	European	Knepper et al.	C22C 38/18
	S	DE (3810448) A1	10-1988	Germany	Burl	384/471
	Т	KR (2005-065911) A	06-2005	Neitherland	Kim et al.	C23C 4/06

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	· ·

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.